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Reassessment of the influence of carrier gases He and Ar on signal intensities in 193 nm excimer LA-ICP-MS analysis

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Fig. S1. The effect of different water vapor introduction rates on the oxide production

rates.



Fig. S2. Comparison of signal intensities obtained at different ablation conditions under He and Ar atmospheres. (a) local extraction ablation cell and dry plasma condition; (b) common cylinder ablation cell and wet plasma condition. The signal intensities obtained in He were normalized to those obtained in Ar.